

Express Mail Label Express Mail No. EV113125568US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: THOMAS L. RITZDORF *et al.*

APPLICATION NO.: 09/612,176

FILED: July 8, 2000

FOR: APPARATUS AND METHOD FOR PROCESSING A
MICROELECTRONIC WORKPIECE USING
METROLOGY

EXAMINER: Zandra V. Smith

ART UNIT: 2877

CONF. NO: 7779

PATENT

RECEIVED
OCT - 8 2002
TECHNOLOGY CENTER 28000Amendment Under 37 C.F.R. § 1.111Assistant Commissioner for Patents
Washington, D.C. 20231

10/03/2002 SMINASS1 00000048 09612176

Sir:

01 FC:103
02 FC:10272.00 DP
84.00 DP

The present communication responds to the Office Action dated June 28, 2002 in the above-identified application. Please amend the application as follows. The attached Appendix presents a marked-up version of the changes made to the claims by the current amendment.

In the Claims:

Please amend claims 1, 13, and 17 as follows and please add new claims 27-30. Following is a complete listing of the claims pending in the application, as amended:

1. (Amended) A processing apparatus for processing a microelectronic workpiece, comprising:

- an in-line metrology unit having a space for receiving a microelectronic workpiece for measuring a condition of a first layer on said microelectronic workpiece and generating a condition signal;
- a control, signal-connected to said metrology unit;
- a process unit providing a space to receive said microelectronic workpiece and performing a material application process that is controlled by said control;